



Shenzhen CTL Testing Technology Co., Ltd.
Tel:+86-755-89486194 E-Mail:ctl@ctl-lab.com

FCC PART 15 Subpart B

Report Reference No.: CTL2212072031-WF

Compiled by

(position+printed name+signature): File administrators Gatsby

Name of the organization performing
the tests

(position+printed name+signature): Technique principal Ivan Xie

Approved by

(position+printed name+signature): Manager Tracy Qi

Date of issue: Jan. 10, 2023

Representative Laboratory Name: Shenzhen CTL Testing Technology Co., Ltd.

Address: Floor 1-A, Baisha Technology Park, No.3011, Shahexi Road, Nanshan District, Shenzhen, China 518055

Test Firm: Shenzhen CTL Testing Technology Co., Ltd.

Address: Floor 1-A, Baisha Technology Park, No.3011, Shahexi Road, Nanshan District, Shenzhen, China 518055

Applicant's name: HighPoint Technologies, Inc.

Address: 41650 Christy Street Fremont, CA 94538

Test specification:

Standard: FCC PART 15 Subpart B

TRF Originator: Shenzhen CTL Testing Technology Co., Ltd.

Shenzhen CTL Testing Technology Co., Ltd.

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Test item description: HighPoint PCIe Gen 3 x8 USB Type-C Controller Card

Model/Type reference: HighPoint RU1244C

List Model(s): N/A

Trade Mark:

Test voltage: Input: 12V

FCC ID: ZHP-RU1244C

Result: Pass



FCC Test Report

Test Report No. :	CTL2212072031-WF	Jan. 10, 2023
		Date of issue

Equipment under Test : HighPoint PCIe Gen 3 x8 USB Type-C Controller Card

Type / Model : HighPoint RU1244C

Listed Models : N/A

Applicant : **HighPoint Technologies, Inc.**

Address : 41650 Christy Street Fremont, CA 94538

Manufacturer : **HighPoint Technologies, Inc.**

Address : 41650 Christy Street Fremont, CA 94538

Test Result	Pass
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The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

History of this test report

Report No.	Version	Description	Issued Date
CTL2212072031-WF	V1.0	Initial Issued Report	Jan. 10, 2023

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1. **TEST STANDARDS**

The tests were performed according to following standards:

[FCC Rules Part 15 Subpart B - Unintentional Radiators](#)

[ANSI C63.4-2014](#)

2. SUMMARY

2.1. General Remarks

Date of receipt of test sample : Dec. 12, 2022

Testing commenced on : Dec. 22, 2022

Testing concluded on : Jan. 10, 2023

2.2. Equipment Under Test

Power supply system utilised

Power supply voltage : 120V / 60 Hz 115V / 60Hz
 12 V DC 5 V DC
 Other (specified in blank below)

/

Description of test modes

The EUT were tested under the following modes, the final worst mode was marked in bold face and recorded in this report.

EMISSION TEST: Radiated Emission

Description of Test Mode	Test Voltage
WORKING	Input: 12V

EMISSION TEST: Conduction Emission

Description of Test Mode	Test Voltage
WORKING	Input: 12V

Note:

For the test results, the EUT had been tested with all conditions. But only the worst case was showed in test report.

2.3. Short description of the Equipment under Test (EUT)

HighPoint PCIe Gen 3 x8 USB Type-C Controller Card.

For more details, refer to the user's manual of the EUT.

2.4. EUT operation mode

The EUT has been tested under typical operating condition.

2.5. EUT configuration

The following peripheral devices and interface cables were connected during the measurement:

- - supplied by the manufacturer
- - supplied by the lab

2.6. Related Submittal(s) / Grant (s)

This test report is intended for HighPoint PCIe Gen 3 x8 USB Type-C Controller Card filing to comply with the FCC Part 15, Subpart B Rules.

2.7. Modifications

No modifications were implemented to meet testing criteria.

2.8. Test Result Summary

Test Item	Test Requirement	Standard Paragraph	Result
Radiated Emission	FCC PART 15 Subpart B	Section 15.109	PASS
Conducted Emission	FCC PART 15 Subpart B	Section 15.107	PASS

3. TEST ENVIRONMENT

3.1. Address of the test laboratory

Shenzhen CTL Testing Technology Co., Ltd.
Floor 1-A, Baisha Technology Park, No. 3011, Shahexi Road, Nanshan, Shenzhen 518055 China

There is one 3m semi-anechoic chamber and two line conducted labs for final test. The Test Sites meet the requirements in documents ANSI C63.4 and CISPR 22/EN 55022 requirements.

3.2. Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

IC Registration No.: 9618B

The 3m alternate test site of Shenzhen CTL Testing Technology Co., Ltd. EMC Laboratory has been registered by Certification and Engineer Bureau of Industry Canada for the performance of with Registration No.: 9618B on November 13, 2013.

FCC-Registration No.: 399832

Shenzhen CTL Testing Technology Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 399832, December 08, 2017.

Certificated by A2LA, USA

Registration No.:4343.01

Date of registration: December 27, 2017

3.3. Environmental conditions

During the measurement the environmental conditions were within the listed ranges:

Temperature:	15-35 ° C
Humidity:	30-60 %
Atmospheric pressure:	950-1050mbar

3.4. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. to CISPR 16 - 4 „Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements“ and is documented in the Shenzhen CTL Testing Technology Co., Ltd quality system acc. to DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

Hereafter the best measurement capability for CTL laboratory is reported:

Test	Range	Measurement Uncertainty	Notes
Radiated Emission(chamber 1)	30~1000MHz	±4.10dB	(1)
Radiated Emission(chamber 2)	30~1000MHz	±4.10dB	(1)
Radiated Emission(chamber 2)	Above 1GHz	±4.32dB	(1)
Conducted Emission	0.15~30MHz	±3.20dB	(1)
Conducted Emission (signal terminal)	0.15~30MHz	±2.96dB	(1)
Disturbance Power	30~300MHz	±2.90dB	(1)

(1) This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3.5. Equipments Used during the Test

Radiated Emission(chamber 1)						
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.Due
1	ULTRA-BROADBAND ANTENNA	Sunol Sciences Corp.	JB1 Antenna	A061713	2020/04/08	2023/04/07
2	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	1166.5950.03	2022/05/06	2023/05/05
Software:						
Name of Software:				Version:		
EZ_EMC				V1.1.4.2		

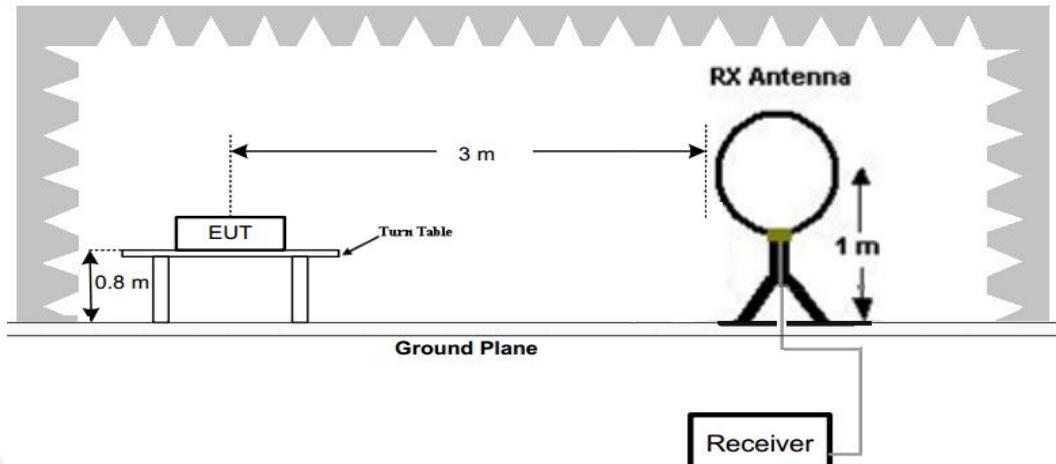
Conducted Emission						
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.Due
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	1166.5950.03	2022/05/06	2023/05/05
2	LISN	ROHDE & SCHWARZ	ESH2-Z5	860014/010	2022/05/06	2023/05/05
3	Limitator	ROHDE & SCHWARZ	ESH3-Z2	1004008	2022/05/06	2023/05/05
4	The Impedance Stability Network ISN	FISCHER CUSTOM COMMUNICATIONS, INC.	F-071115-1057-1-09	112299	2022/05/06	2023/05/05
Software:						
Name of Software:				Version:		
ES-K1				V1.71		

4 TEST CONDITIONS AND RESULTS

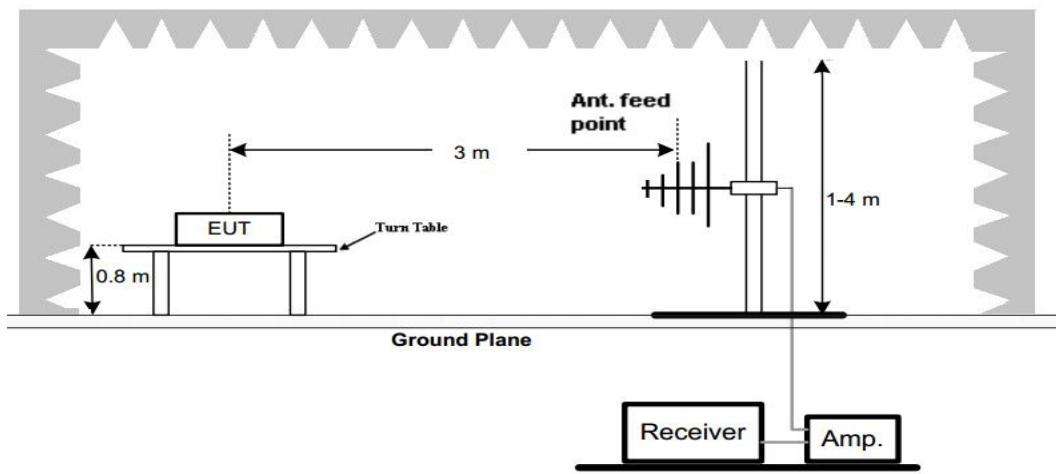
4.1. Radiated Emission Test

TEST CONFIGURATION

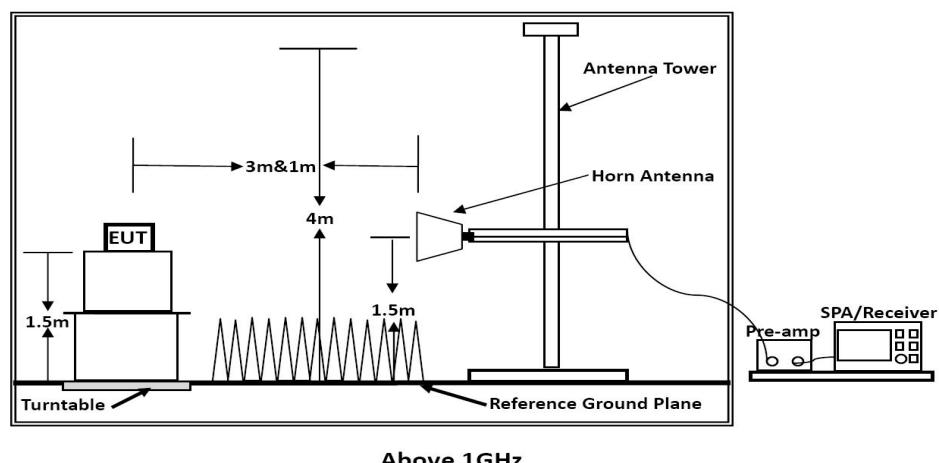
Radiated Emission Test Set-Up, Frequency Below 30MHz



Radiated Emission Test Set-Up, Frequency below 1000MHz



Radiated Emission Test Set-Up, Frequency above 1000MHz



Above 1GHz

Field Strength Calculation

The field strength is calculated by adding the Antenna Factor and Cable Factor and subtracting the Amplifier Gain and Duty Cycle Correction Factor(if any) from the measured reading. The basic equation with a sample calculation is as follows:

$$FS = RA + AF + CL - AG$$

Where FS = Field Strength	CL = Cable Attenuation Factor (Cable Loss)
RA = Reading Amplitude	AG = Amplifier Gain
AF = Antenna Factor	

RADIATION LIMIT

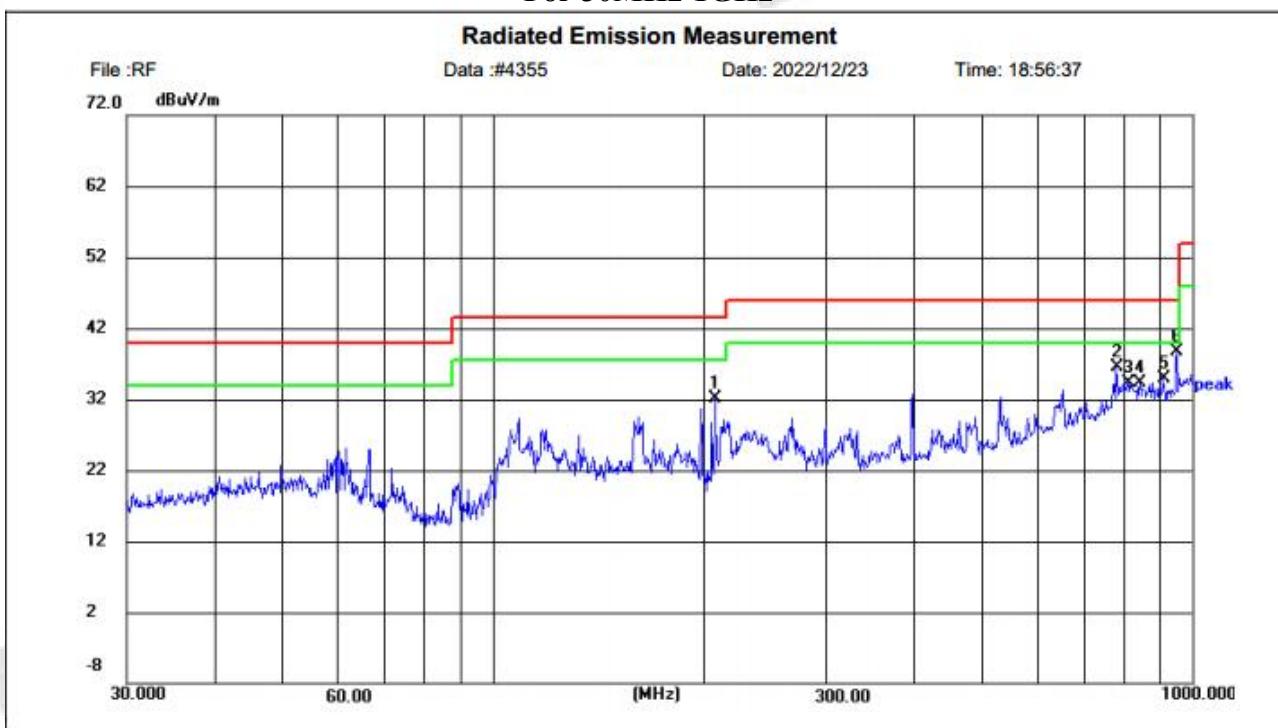
For unintentional device, according to § 15.109(a), except for Class A digital devices, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency (MHz)	Distance (Meters)	Radiated (dB μ V/m)	Radiated (μ V/m)
30-88	3	40.0	100
88-216	3	43.5	150
216-960	3	46.0	200
960	3	54.0	500

For intentional device, according to § 15.209(a), the general requirement of field strength of radiated emissions from intentional radiators at a distance of 3 meters shall not exceed the above table.

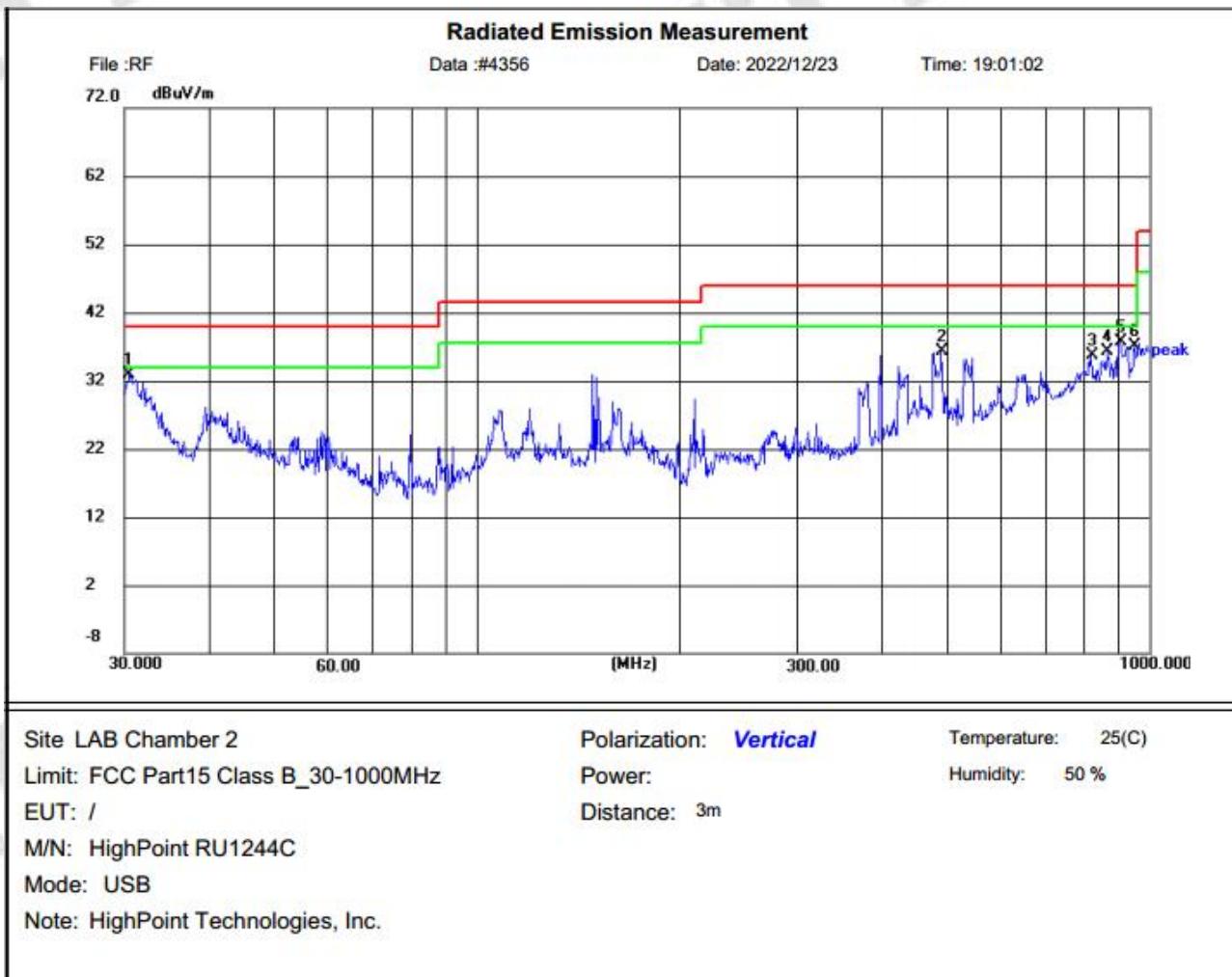
Test Procedure

1. The EUT is placed on a turntable, which is 0.8m above ground plane.
2. The turntable shall be rotated for 360 degrees to determine the position of maximum emission level.
3. EUT is set 3m away from the receiving antenna, which is varied from 1m to 4m to find out the highest emissions.
4. Maximum procedure was performed on the six highest emissions to ensure EUT compliance.
5. And also, each emission was to be maximized by changing the polarization of receiving antenna both horizontal and vertical.
6. Repeat above procedures until the measurements for all frequencies are complete.

Radiation Test Results**For 30MHz-1GHz**

Site LAB Chamber 2	Polarization: Horizontal	Temperature: 25(C)
Limit: FCC Part15 Class B_30-1000MHz	Power:	Humidity: 50 %
EUT: /	Distance: 3m	
M/N: HighPoint RU1244C		
Mode: USB		
Note: HighPoint Technologies, Inc.		

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	207.8501	20.73	11.30	32.03	43.50	11.47	peak	100	231	P	
2	779.6068	12.23	24.29	36.52	46.00	9.48	peak	100	44	P	
3	810.2654	9.36	24.93	34.29	46.00	11.71	peak	100	52	P	
4	842.1296	8.99	25.35	34.34	46.00	11.66	peak	100	223	P	
5	909.6667	8.71	26.11	34.82	46.00	11.18	peak	100	352	P	
6	952.0937	12.07	26.57	38.64	46.00	7.36	peak	100	319	P	

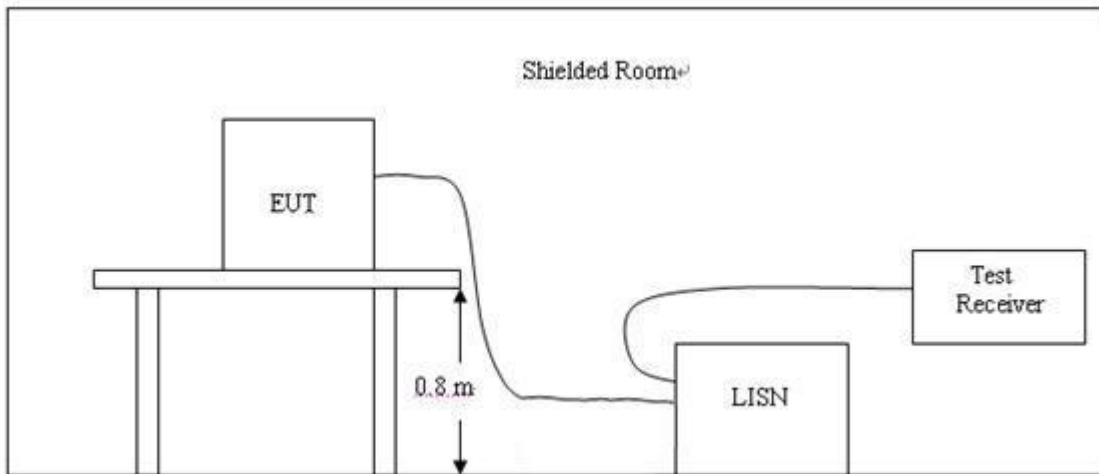


No.	Frequency (MHz)	Reading (dB _{UV})	Factor (dB/m)	Level (dB _{UV} /m)	Limit (dB _{UV} /m)	Margin (dB)	Detector	Height (cm)	Azimuth (deg.)	P/F	Remark
1	30.5306	20.99	12.01	33.00	40.00	7.00	peak	100	290	P	
2	490.7447	17.77	18.46	36.23	46.00	9.77	peak	100	315	P	
3	818.8341	10.74	25.05	35.79	46.00	10.21	peak	100	331	P	
4	866.0879	10.68	25.62	36.30	46.00	9.70	peak	100	323	P	
5	903.3094	11.59	26.04	37.63	46.00	8.37	peak	100	347	P	
6	952.0937	10.49	26.57	37.06	46.00	8.94	peak	100	25	P	

Note: The internal working frequency of the product is not more than 108MHz, and the test above 1GHz is not required.

4.2. Conducted Emissions Test

TEST CONFIGURATION



TEST PROCEDURE

- 1 The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. The EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per ANSI C63.4.
- 2 Support equipment, if needed, was placed as per ANSI C63.4.
- 3 All I/O cables were positioned to simulate typical actual usage as per ANSI C63.4.
- 4 The EUT received power through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.
- 5 All support equipments received AC power from a second LISN, if any.
- 6 The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7 Analyzer / Receiver scanned from 150 KHz to 30MHz for emissions in each of the test modes.
- 8 During the above scans, the emissions were maximized by cable manipulation.

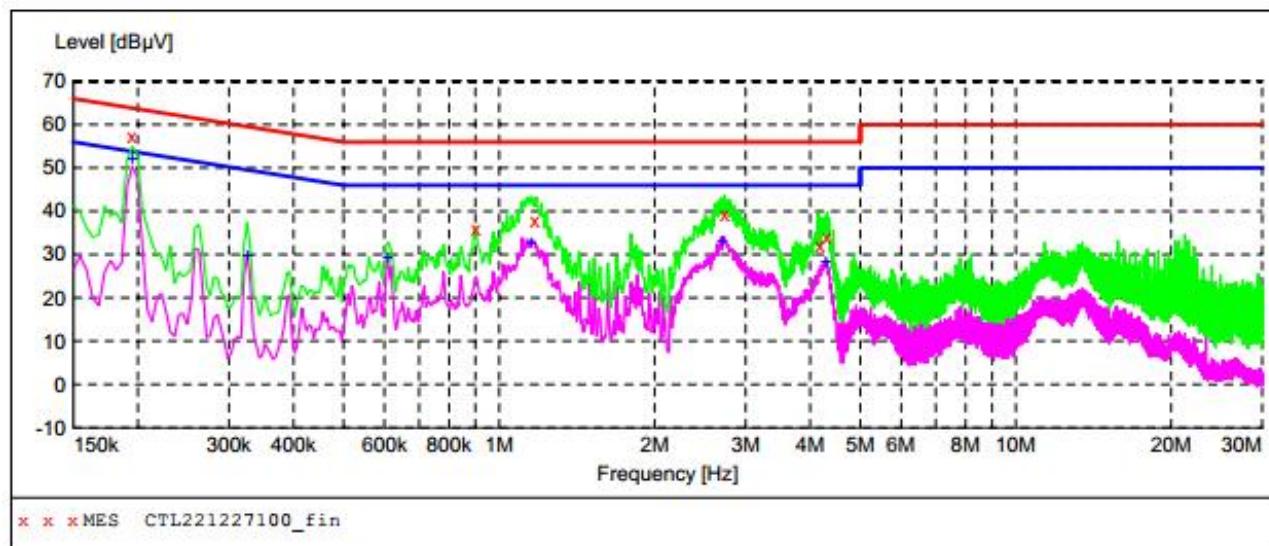
Conducted Power Line Emission Limit

For unintentional device, according to § 15.107(a) Line Conducted Emission Limits is as following :

Frequency (MHz)	Maximum RF Line Voltage (dB μ V)			
	CLASS A		CLASS B	
	Q.P.	Ave.	Q.P.	Ave.
0.15 - 0.50	79	66	66-56*	56-46*
0.50 - 5.00	73	60	56	46
5.00 - 30.0	73	60	60	50

* Decreasing linearly with the logarithm of the frequency

For intentional device, according to §15.207(a) Line Conducted Emission Limit is same as above table.

TEST RESULTS**SCAN TABLE: "Voltage (9K-30M) FIN"**
Short Description: 150K-30M Voltage**MEASUREMENT RESULT: "CTL221227100_fin"**

12/27/2022 6:38PM

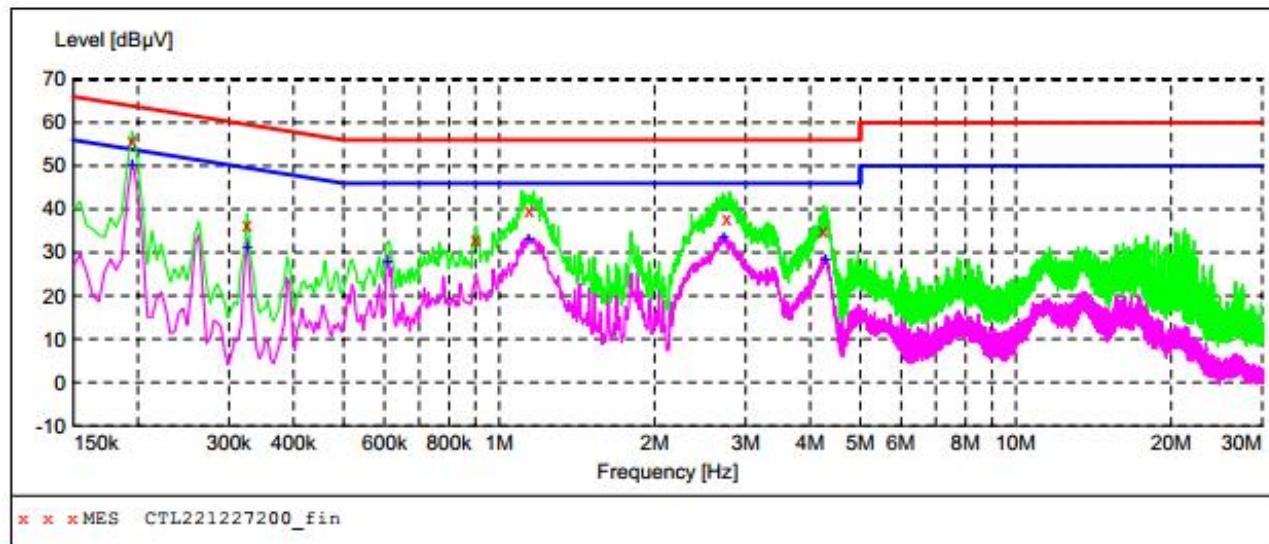
Frequency MHz	Level dB μ V	Transd dB	Limit dB μ V	Margin dB	Detector	Line	PE
0.195000	57.30	10.0	64	6.5	QP	L1	GND
0.901500	36.10	10.1	56	19.9	QP	L1	GND
1.176000	37.90	10.1	56	18.1	QP	L1	GND
2.737500	39.10	10.1	56	16.9	QP	L1	GND
4.182000	32.30	10.2	56	23.7	QP	L1	GND
4.312500	34.20	10.2	56	21.8	QP	L1	GND

MEASUREMENT RESULT: "CTL221227100_fin2"

12/27/2022 6:38PM

Frequency MHz	Level dB μ V	Transd dB	Limit dB μ V	Margin dB	Detector	Line	PE
0.195000	52.20	10.0	54	1.6	AV	L1	GND
0.325500	29.90	10.1	50	19.7	AV	L1	GND
0.609000	29.30	10.1	46	16.7	AV	L1	GND
1.153500	32.60	10.1	46	13.4	AV	L1	GND
2.701500	32.90	10.1	46	13.1	AV	L1	GND
4.290000	28.40	10.2	46	17.6	AV	L1	GND

SCAN TABLE: "Voltage (9K-30M) FIN"
 Short Description: 150K-30M Voltage



MEASUREMENT RESULT: "CTL221227200_fin"

12/27/2022 6:41PM

Frequency MHz	Level dB μ V	Transd dB	Limit dB μ V	Margin dB	Detector	Line	PE
0.195000	55.70	10.0	64	8.1	QP	N	GND
0.325500	36.50	10.1	60	23.1	QP	N	GND
0.901500	33.30	10.1	56	22.7	QP	N	GND
1.144500	39.70	10.1	56	16.3	QP	N	GND
2.764500	38.00	10.1	56	18.0	QP	N	GND
4.249500	34.80	10.2	56	21.2	QP	N	GND

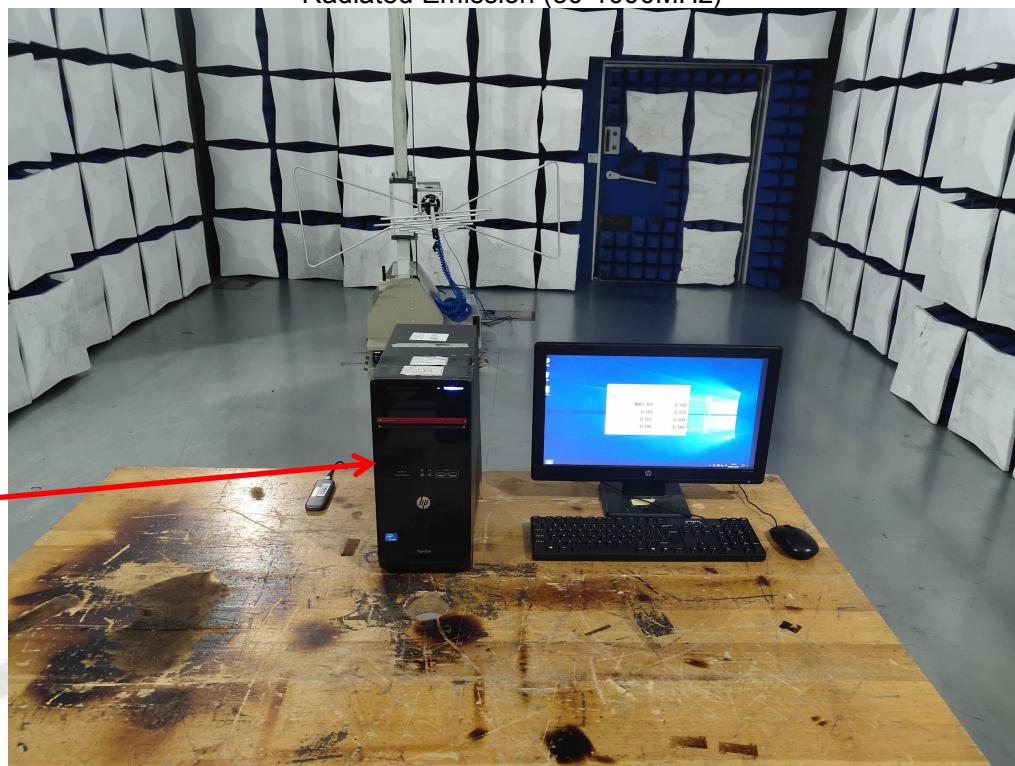
MEASUREMENT RESULT: "CTL221227200_fin2"

12/27/2022 6:41PM

Frequency MHz	Level dB μ V	Transd dB	Limit dB μ V	Margin dB	Detector	Line	PE
0.195000	50.30	10.0	54	3.5	AV	N	GND
0.325500	31.40	10.1	50	18.2	AV	N	GND
0.609000	27.90	10.1	46	18.1	AV	N	GND
1.140000	33.10	10.1	46	12.9	AV	N	GND
2.719500	33.60	10.1	46	12.4	AV	N	GND
4.276500	28.50	10.2	46	17.5	AV	N	GND

5. Test Setup Photos of the EUT

Radiated Emission (30-1000MHz)

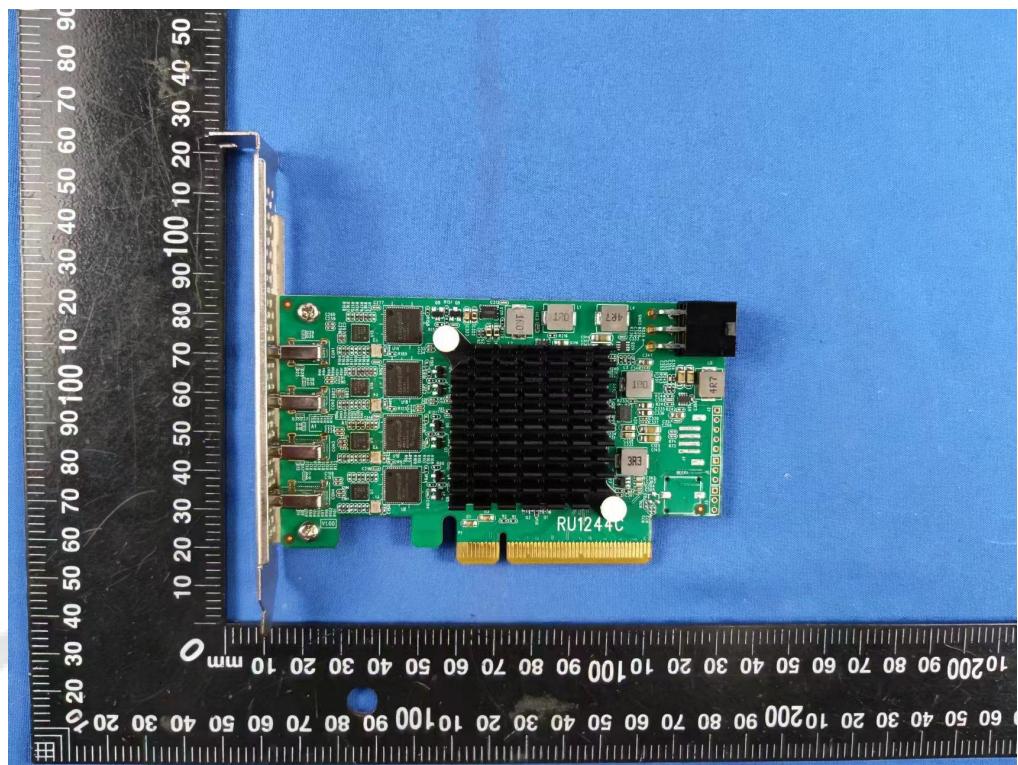


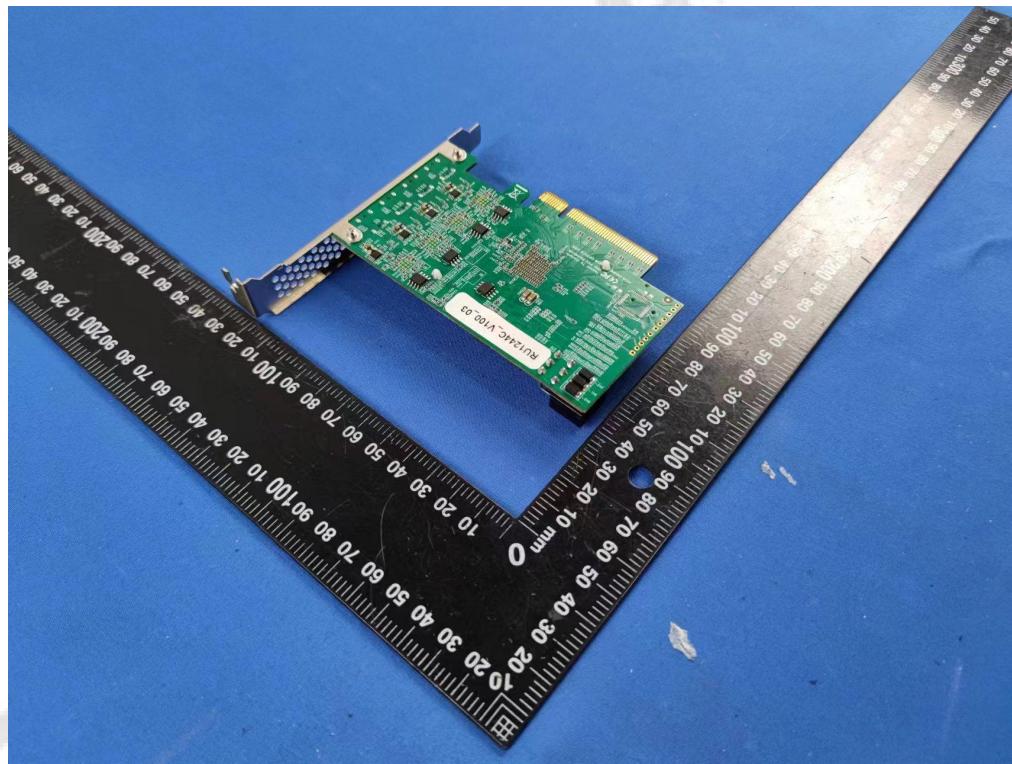
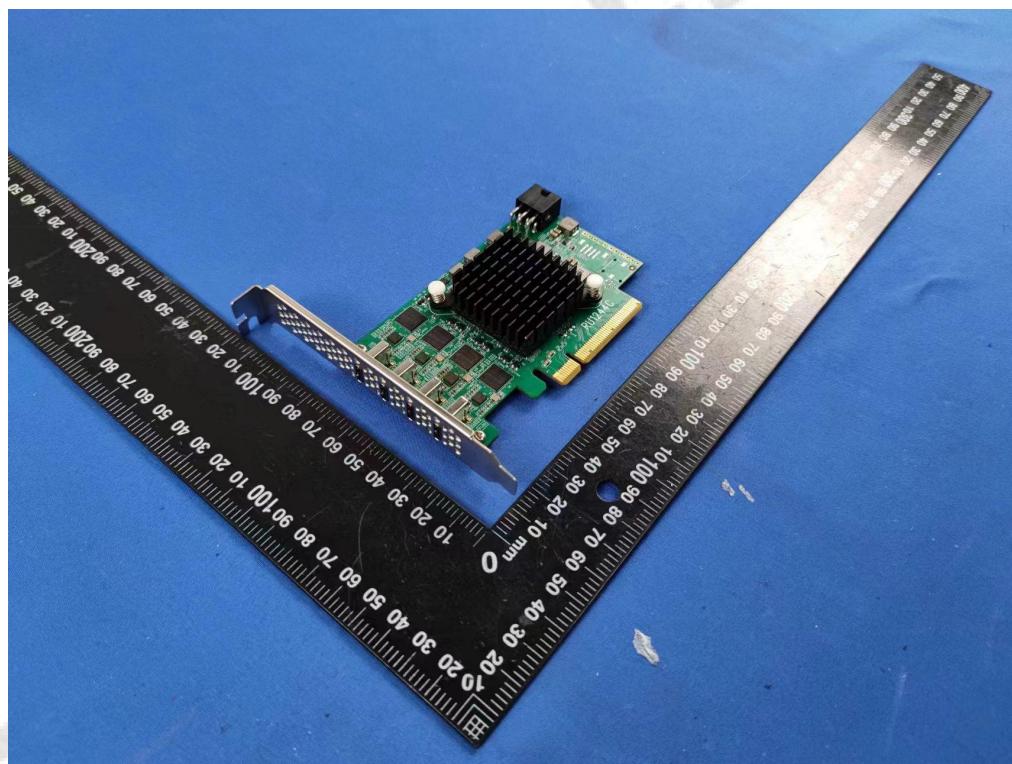
The product
is inside the
computer
host.

Conducted Emission



6. Photos of the EUT





.....End of Report.....